Workshop on Nano Probe Techniques

10 April 2015

Venue:
PBCEC,
Indian Institute of Technology
Kanpur, India

Organized by
IIT-Kanpur & CAMECA

Objective
The workshop aims at providing basic and advanced knowledge of Secondary Ion Mass Spectroscopy (SIMS) and Atom Probe Tomography (APT) and their applications. The technical talks by eminent experts on SIMS will cover the depth profile, 2D & 3D, isotopic ratio and mass spectrum analytical outputs. The talks on APT will cover the extensive capabilities of the technique for both 3D imaging and chemical composition at the atomic scale.

Who can attend?
Research scholars and young faculty members working in the area of Physics, Chemistry, Materials Science and Engineering as well as Earth Science are eligible to participate.

Registration
Confirm your participation by email to sivaudct@gmail.com by 15th March 2015.

Invited speakers

Atom Probe Tomography Session
Dr. Peter Clifton, CAMECA USA
Dr. S. Ranganathan & Dr. Chandan Srivastava,
Dpt of Materials Engineering,
IISc-Bangalore
Dr. Anirudh Biswas, BARC-Mumbai
Dr. R. Gopalan, Head Centre for Automotive Energy Materials, International Advanced Research Centre for Powder Metallurgy and New Materials (ARCI), Chennai.

Secondary Ion Mass Spectroscopy Session
Dr. Philippe Saliot, CAMECA France
Dr. A. K. Tyagi, Head surface and Nano Science Division, Materials, Science Group. IGCAR.
Dr. Anuradha Dhaul, Group-Characterization Division, SSPL-New Delhi
Dr. G.Srinivasan,
Former Professor, University of Toronto, Canada
Dr. R. Gopalan, Head Centre for Automotive Energy Materials, International Advanced Research Centre for Powder Metallurgy and New Materials (ARCI), Chennai.

Dr. Sundar, Materials Science Programme, IIT-Kanpur.

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